

	Application/Control No.	Applicant(s)/Patent under Reexamination
•	10/804,171	CHO ET AL.
	Examiner	Art Unit
	Davida I Duff	2740

SEARCHED					
Class	Subclass	Date	Examiner		
418	60	2/22/2007	DJD		
418	32	2/22/2007	DJD		
418	2	2/22/2007	DID		
418	30	2/22/2007	DJD		
418	28 .	2/22/2007	DJD		
418	29	2/22/2007	DJD		
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INT	INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner			
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST (US-PGPUB, USPAT, USOCR, FPRS, EPO, JPO, DERWENT)	2/22/2007	DJD		
Consulted T. Trieu for search subclasses	2/22/2007	DJD		
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